Notice of References Cited Application/Control No. 10/620,290 Examiner Art Unit Maria Veronica D. Ewald Applicant(s)/Patent Under Reexamination MEYER, HELMUT Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,222,816	06-1993	Kondoh et al.	384/463
	В	US-6,203,207	03-2001	Yamamoto et al.	384/492
	С	US-3,980,418	09-1976	Schott, Jr., Charles M.	425/72.1
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-		,	

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0		-				
	Р						
	Q						
	R						
	s						
	Т						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	w	,					
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.